

ITW

Docket No.: WEN-0032
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yoshiaki MIMURA et al

Application No.: 10/811,824

Conf. No. 3065

Filed: March 30, 2004

Art Unit: 3737

For: OPTHALMIC APPARATUS

Examiner: Not Yet Assigned

SECOND INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

Dear Sir:

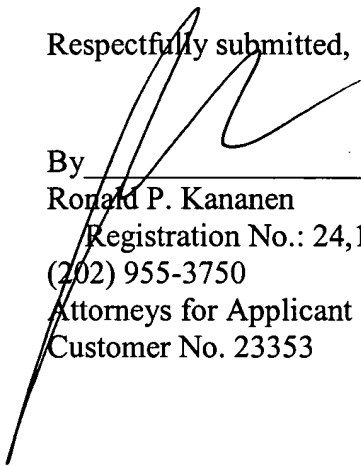
The Applicant, through its representatives and attorneys, hereby brings to the attention of the Examiner the additional four (4) documents noted on the accompanying Form PTO-1449. Copies are provided.

This will certify that each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement. Specifically, these documents were noted in a European Search Report (ESR) issued on July 16, 2004 in connection with the corresponding European application. A copy of the ESR is provided for the convenience of the Examiner.

Please take these additional documents into account when reaching this application for consideration on its merits, and make their consideration of record.

Dated: September 10, 2004

Respectfully submitted,



By _____
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PTO/SB/08a/b (08-03)

Approved for use through 07/31/2006. OMB 0651-0031

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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/811,824
				Filing Date	March 30, 2004
				First Named Inventor	Yoshiaki Mimura
				Art Unit	3737
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	WEN-0032

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)	MM-DD-YYYY		
		5,689,325	11/18/97	Isogai et al	
		5,909,269	06/01/99	Isogai et al	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
	BA	EP 0 310 045 A1	04/05/89	Canon Kabushiki Kaisha		
	BB	EP 0 850 591 A1	07/01/98	Nidek Co., Ltd.		
	BC					
	BD					
	DE					
	DF					
	DG					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
	CA	EPO Search Report dated July 16, 2004			

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¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
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